N-Channel Enhancement Mode Power MOSFET

Description

The HM40N20 uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications.

General Features

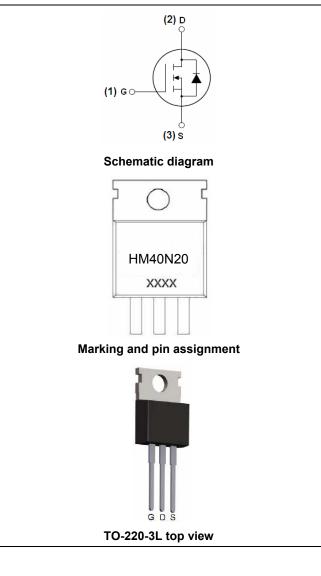
- V_{DS} =200V,I_D =40A
 R_{DS(ON)} <41mΩ @ V_{GS}=10V
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

100% UIS TESTED!

100% ΔVds TESTED!



Package Marking And Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM40N20	HM40N20	TO-220-3L	-	-	-

Absolute Maximum Ratings (TA=25°C unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	Vds	200	V	
Gate-Source Voltage	Vgs	±20	V	
Drain Current-Continuous	I _D	40	А	
Drain Current-Continuous(T _C =100 ℃)	I _D (100℃)	28	А	
Pulsed Drain Current	I _{DM}	160	А	
Maximum Power Dissipation	PD	220	W	
Derating factor		1.47	₩/°C	
Single pulse avalanche energy (Note 5)	E _{AS}	480	mJ	
Operating Junction and Storage Temperature Range	TJ,TSTG	-55 To 175	°C	

Thermal Characteristic

Thermal Resistance, Junction-to-Case(Note 2)	R _{θJC}	0.68	°C/W	l
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Electrical Characteristics (TA=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics			•			
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250µA	200	220	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =200V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)	·					
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} ,I _D =250µA	2	3.2	4	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =20A	-	36.4	41	mΩ
Forward Transconductance	g fs	V _{DS} =25V,I _D =25A	26	-	-	S
Dynamic Characteristics (Note4)	·					
Input Capacitance	C _{lss}		-	6500	-	PF
Output Capacitance	Coss	V _{DS} =25V,V _{GS} =0V, F=1.0MHz	-	290	-	PF
Reverse Transfer Capacitance	C _{rss}		-	220	-	PF
Switching Characteristics (Note 4)	·					
Turn-on Delay Time	t _{d(on)}		-	26	-	nS
Turn-on Rise Time	tr	V_{DD} =30V,I _D =2A,R _L =15Ω	-	24	-	nS
Turn-Off Delay Time	t _{d(off)}	V _{GS} =10V,R _G =2.5Ω	-	91	-	nS
Turn-Off Fall Time	t _f		-	39	-	nS
Total Gate Charge	Qg)/ -20)/ -20)	-	163		nC
Gate-Source Charge	Q _{gs}	V _{DS} =30V,I _D =30A, V _{GS} =10V	-	31		nC
Gate-Drain Charge	Q _{gd}	VGS-10V	-	64		nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =40A	-		1.2	V
Diode Forward Current (Note 2)	Is		-	-	40	А
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF = 40A	-	42		nS
Reverse Recovery Charge	Qrr	di/dt = 100A/µs(Note3) - 66			nC	
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negli	gible (turi	n-on is do	pminated b	y LS+LD)

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.

2. Surface Mounted on FR4 Board, $t \le 10$ sec.

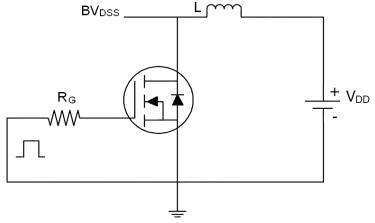
3. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2%.

4. Guaranteed by design, not subject to production

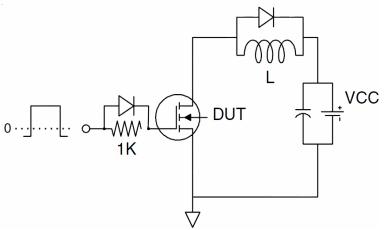
5. EAS condition: Tj=25 $^{\circ}$ C,V_{DD}=50V,V_G=10V,L=1mH,Rg=25 Ω

Test circuit

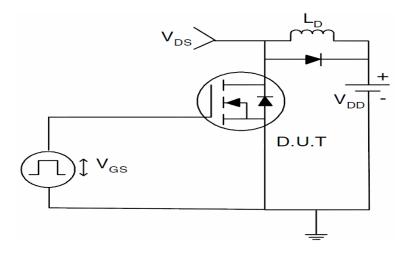
1) E_{AS} test Circuits

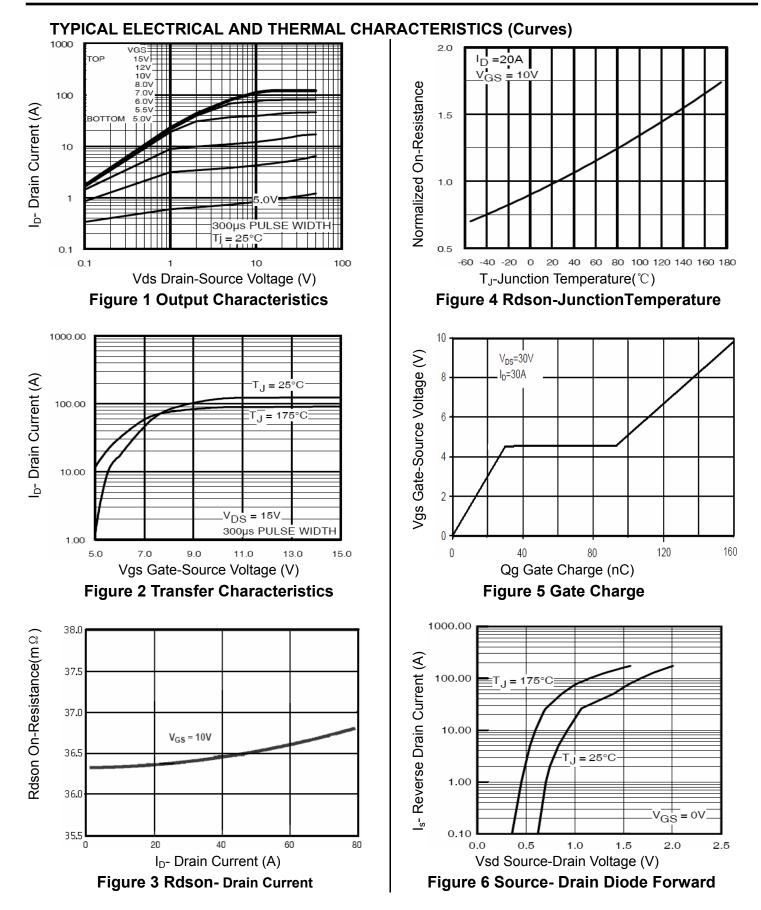


2) Gate charge test Circuit:

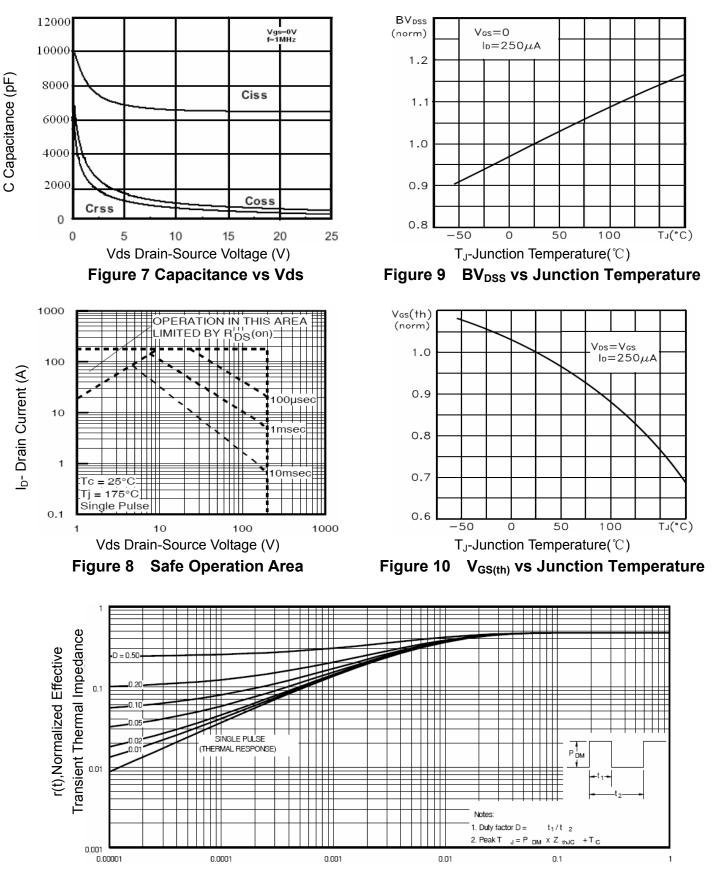


3) Switch Time Test Circuit:





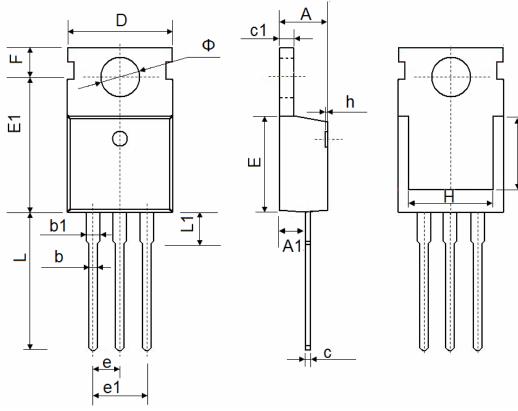
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Square Wave Pluse Duration(sec) Figure 11 Normalized Maximum Transient Thermal Impedance

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Cumph al	Dimensions I	n Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
А	4.400	4.600	0.173	0.181	
A1	2.250	2.550	0.089	0.100	
b	0.710	0.910	0.028	0.036	
b1	1.170	1.370	0.046	0.054	
С	0.330	0.650	0.013	0.026	
c1	1.200	1.400	0.047	0.055	
D	9.910	10.250	0.390	0.404	
E	8.9500	9.750	0.352	0.384	
E1	12.650	12.950	0.498	0.510	
е	2.540	2.540 TYP.		TYP.	
e1	4.980	5.180	0.196	0.204	
F	2.650	2.950	0.104	0.116	
Н	7.900	8.100	0.311	0.319	
h	0.000	0.300	0.000	0.012	
L	12.900	13.400	0.508	0.528	
L1	2.850	3.250	0.112	0.128	
V	7.500 REF.		0.295 REF.		
Φ	3.400	3.800	0.134	0.150	

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